

# AN13523

## LPC553x/LPC55S3x ADC with Hardware Trigger and ADC Calculator Tool

Rev. 1 — 20 April 2022

Application Note

### 1 Introduction

The LPC553x/LPC55S3x MCU family is part of the EdgeVerse edge computing platform and builds on the world's first general-purpose Cortex-M33 based microcontroller introduced with the LPC5500 series. LPC553x/LPC55S3x uses a 16-bit Analog-to-Digital Converter (ADC) which is a dual successive approximation ADC. The ADC allows for differential 16/13-bit resolution and single-ended 16/12-bit resolution operations.

This application note introduces the ADC features that are available with the LPC553x/LPC55S3x device as well as the attached tool to calculate sampling time or source impedance. In addition, an example is provided to demonstrate the hardware triggering capability implemented with the Input Multiplexing (INPUTMUX) module using the CTimer to trigger ADC conversions.

### 2 ADC features

The ADC module has the following features available on two instances, ADC0 and ADC1:

- Linear successive approximation algorithm
- Differential operation with 16-bit or 13-bit resolution
- Single-ended operation with 16-bit or 12-bit resolution
- Support for two simultaneous single ended conversions.

There is channel support for analog input channels (up to 20 channels) for conversion of external pins and from internal sources. It has a configurable analog input sample time, as well as speed options to accommodate low-power modes. It is capable of having up to 4 trigger sources with different priority.

The ADC module supports three different modes of operation.

Table 1. Different modes of operation

Modes	Description
Run	Normal Operation
Deep-sleep or Sleep	Can continue operating provided the Doze Enable bit (CTRL[DOZEN]) is clear and the module is using an external or internal clock source which remains operating during Deep-sleep/Sleep modes.
Deep Power-down	The Doze Enable (CTRL[DOZEN]) bit is ignored and the module waits for the current transfer to complete any pending operation before acknowledging Deep Power-down mode entry.

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### 3 ADC trigger interconnections

ADC command execution is initiated from up to 4 trigger sources. Each trigger can be software generated by writing 0b1 to the corresponding SWTRIG[SWTn] bit field. Alternatively, hardware triggers can be generated from asynchronous input sources at the periphery of the module. For example, we can use a PWM signal to trigger a conversion periodically. When a hardware trigger input is enabled, hardware trigger events are detected on the rising-edge of the associated hardware trigger source. Each trigger source is assigned a priority via the associated priority control field (TCTRLa[TPRI]). Each of the trigger sources is associated with a command buffer via the associated command select field (TCTRLa[TCMD]).

INPUTMUX provides signal routing options for internal peripherals. Some peripheral inputs are multiplexed to multiple input sources. The sources can be external pins, interrupts, output signals of other peripherals, or other internal signals.

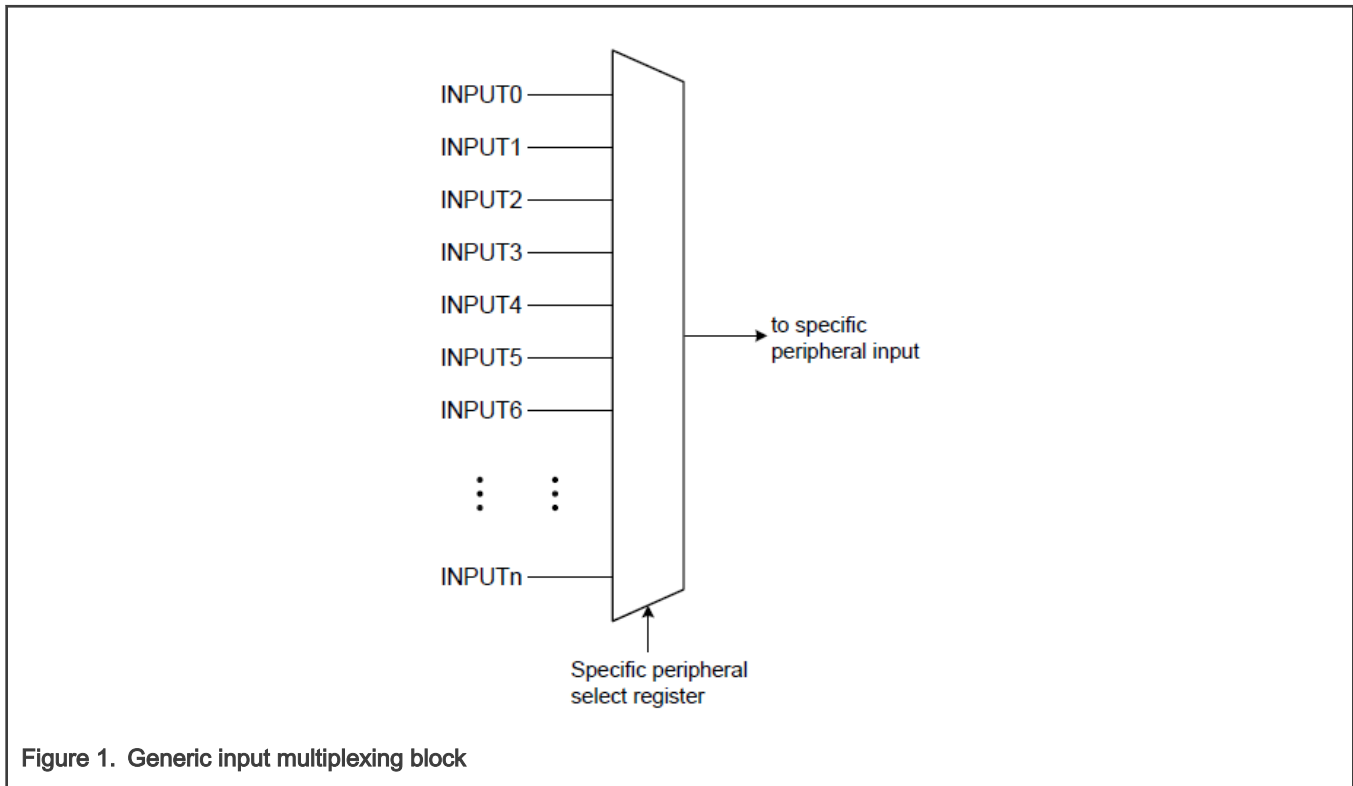


Figure 1. Generic input multiplexing block

The ADC has multiple options for both instances, ADC0 and ADC1, to trigger the analog conversions. The four ADC0 Trigger input connections can be chosen from the list found in the “ADCn Trigger Input Connections ADCn\_TRIG0-ADCn\_TRIG3” section from the LPC553x/LPC55S3x Reference Manual. This document focuses on using the CTimer as a trigger.

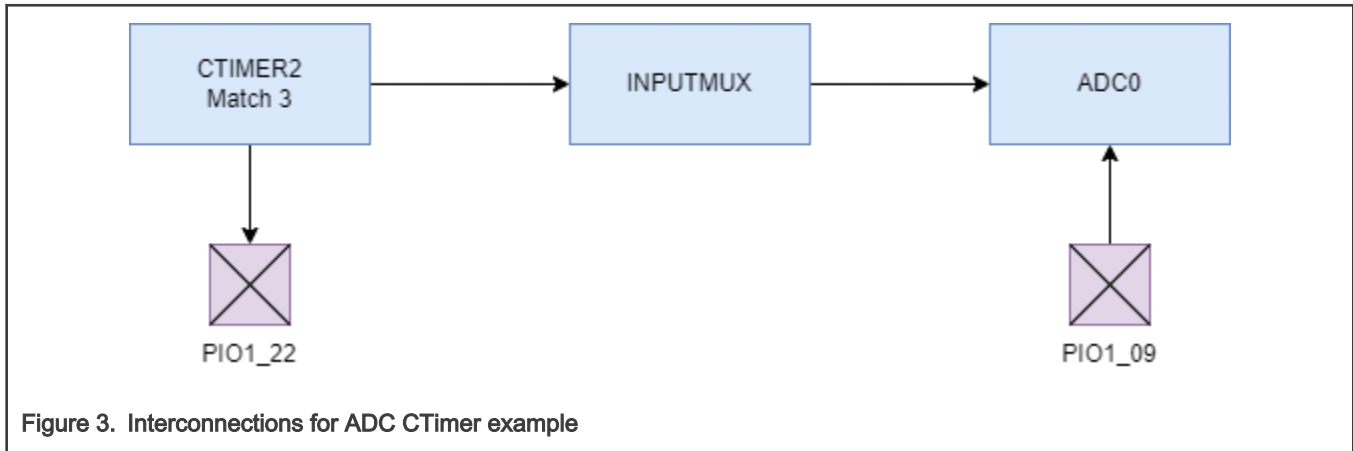
000101 - T0_MAT3
000110 - T1_MAT3
000111 - T2_MAT3
001000 - T3_MAT3
001001 - T4_MAT3

Figure 2. CTimer trigger options for ADC0

## 4 ADC CTimer example

For this example, the following three modules are set up: ADC, CTimer, and the INPUTMUX. This example is created with the SDK version 2.10.2 using MCUXpresso 11.4.1.

Although it is not necessary to assign an external pin for the CTIMER, in this example, the PIO1\_22 is used in order to verify the behavior of the CTIMER. In addition, the ADC0 uses an external pin to measure an external analog source. A simple block diagram of the example is as shown below.



The ADC is configured in the following manner.

ADC input frequency is 5.7 MHz connected from the PLL0 clock which is configured to be at 45.8 MHz. It is recommended to use low frequencies to execute the calibration flow. Select 128 ADC conversions which are averaged to calculate each calibration value. Selecting a higher number of averages leads to more accurate conversions after completing calibration. ADC analog circuits are pre-enabled and ready to execute conversions without startup delays (at the cost of higher DC current consumption). The reference voltage is the voltage on the VDDA pin.

```

/*Attaching low frequency clock from PLL for calibration purposes: ADC0 Frequency at 5.7MHz*/
CLOCK_SetClkDiv(kCLOCK_DivAdc0Clk, 0U, true);          /*!< Reset ADC0CLKDIV divider counter and halt it */
CLOCK_SetClkDiv(kCLOCK_DivAdc0Clk, 8U, false);        /*!< Set ADC0CLKDIV divider to value 8 */
CLOCK_AttachClk(kPLL0_to_ADC0);                       /*!< Switch ADC0 to PLL0 */

/* Disable VREF power down */
POWER_DisablePD(kPDRUNCFG_PD_VREF);

LPADC_GetDefaultConfig(&mLpadcConfigStruct);
mLpadcConfigStruct.enableAnalogPreliminary = true;
mLpadcConfigStruct.referenceVoltageSource = kLPADC_ReferenceVoltageAlt3;
mLpadcConfigStruct.conversionAverageMode = kLPADC_ConversionAverage128;
LPADC_Init(DEMO_LPADC_BASE, &mLpadcConfigStruct);
  
```

**Figure 4. ADC configuration**

Once the auto-calibration is finished, you can choose a higher frequency clock for the ADC. In this example, we use 48 MHz. The command configuration is set for channel 0 associated to the A-side using a high-resolution conversion. This selects analog signal ADC0IN0A for conversion, available on pin PIO1\_9. Each ADC command independently makes a channel and conversion type selection. In this example, single ended operation is chosen. However, it is possible to convert to differential mode but only limited pairs are intended to be set as differential channels. Refer to the LPC553x/LPC55S3x Reference Manual for the available pin pairings. Additionally, the trigger configuration is set to hardware trigger since, we are using another module's signal to trigger the ADC conversions.

```

/* Set conversion CMD configuration. */
LPADC_GetDefaultConvCommandConfig(&mLpadcCommandConfigStruct);
mLpadcCommandConfigStruct.channelNumber = 0U;
mLpadcCommandConfigStruct.sampleChannelMode = kLPADC_SampleChannelSingleEndSideA;
mLpadcCommandConfigStruct.conversionResolutionMode = kLPADC_ConversionResolutionHigh;

LPADC_SetConvCommandConfig(DEMO_LPADC_BASE, DEMO_LPADC_USER_CMDID, &mLpadcCommandConfigStruct);

/* Set trigger configuration. */
LPADC_GetDefaultConvTriggerConfig(&mLpadcTriggerConfigStruct);
mLpadcTriggerConfigStruct.targetCommandId = 1U;
mLpadcTriggerConfigStruct.enableHardwareTrigger = true;
LPADC_SetConvTriggerConfig(DEMO_LPADC_BASE, 0U, &mLpadcTriggerConfigStruct); /* Configure the trigger0. */

```

Figure 5. LPADC CMD and trigger configuration

The CTimer is configured in the following manner:

CTimer input frequency is 96 MHz. From the trigger options that are available for the ADC0 instance, we can configure any CTimer0 - CTimer4 Match 3 signal, in this case CTimer 2 Match 3 is used. It is configured as timer mode and increments on every APB bus clock. The counter is reset after every match and toggles the output at a frequency of 1 kHz. It is not necessary to enable the interrupt for the CTimer, since we are attaching the signal regardless to the ADC trigger. However, if it is necessary to change the match value or other setting of the CTimer, you may enable an interrupt for additional actions that may be required.

```

/* Use 96MHz clock for CTimer2*/
CLOCK_SetClkDiv(kCLOCK_DivCtimer2Clk, 0u, false);
CLOCK_SetClkDiv(kCLOCK_DivCtimer2Clk, 1u, true);
CLOCK_AttachClk(kFRO_HF_to_CTIMER2);

CTIMER_GetDefaultConfig(&config);

CTIMER_Init(CTIMER, &config);

/* Configuration 0 */
matchConfig0.enableCounterReset = true;
matchConfig0.enableCounterStop = false;
matchConfig0.matchValue = CTIMER_CLK_FREQ / 2000;
matchConfig0.outControl = kCTIMER_Output_Toggle;
matchConfig0.outPinInitState = false;
matchConfig0.enableInterrupt = false;

CTIMER_SetupMatch(CTIMER, CTIMER_MAT3_OUT, &matchConfig0);
CTIMER_StartTimer(CTIMER);

```

Figure 6. CTimer configuration

The INPUTMUX is configured in the following manner:

The INPUTMUX module needs to be initialized prior to attaching the appropriate signals. In this case, we are using the CTIMER2 Match 3 signal to trigger the ADC0 instance.

```

INPUTMUX_Init(INPUTMUX);
INPUTMUX_AttachSignal(INPUTMUX, 0U, kINPUTMUX_Ctimer2M3ToAdc0Trigger);

```

Figure 7. INPUTMUX configuration

By checking the CTimer external pin (PIO1\_22, at header J10 pin 9 on LPC55S36-EVK), it is possible to verify that the signal is effectively working as expected. It is toggling at a rate of 1 kHz. As discussed previously, each ADC conversion is triggered on the

rising edge of the CTimer waveform that is seen below. The three blue arrows in the image below represent rising edges where the ADC0 is being triggered.

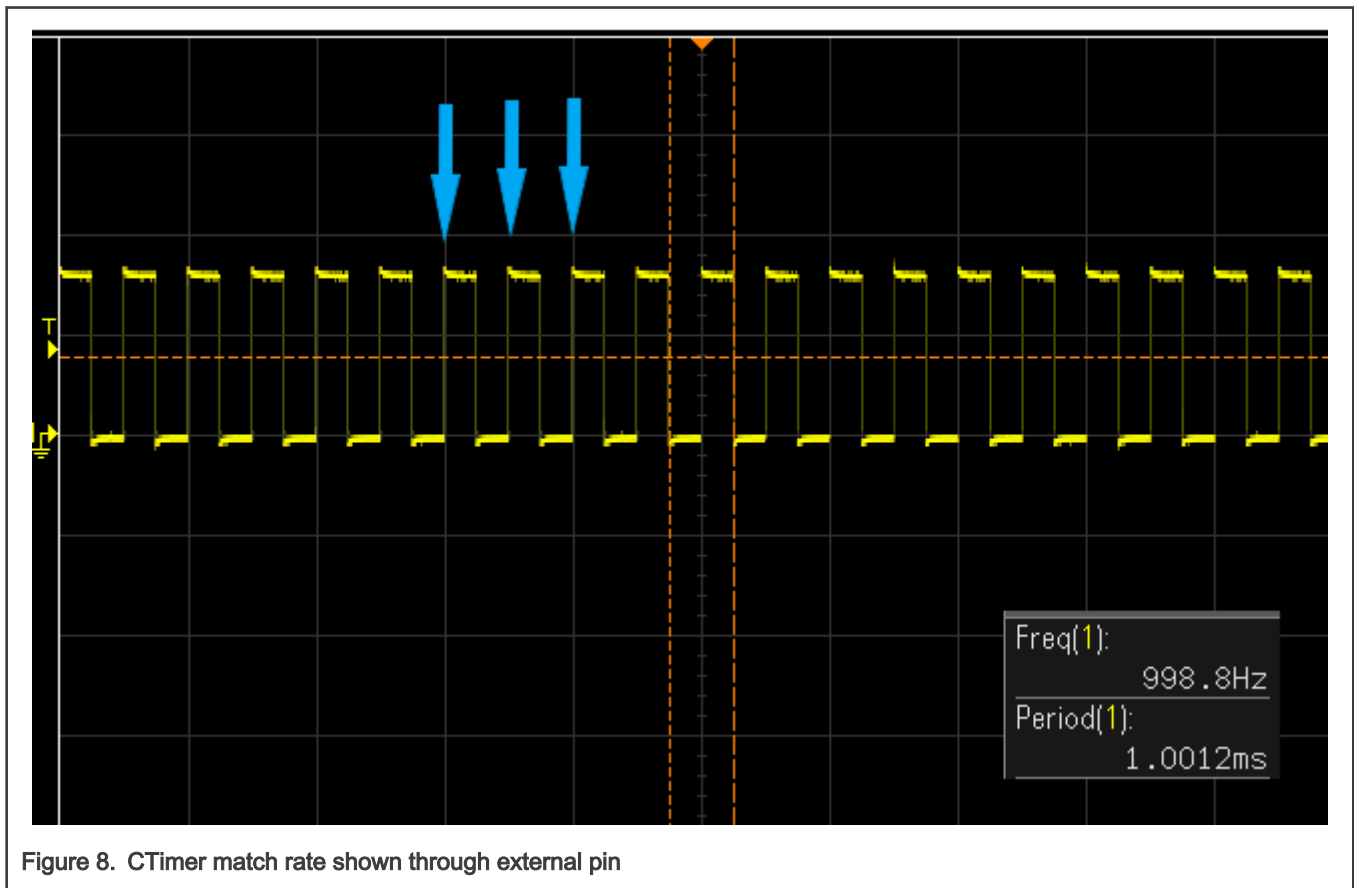


Figure 8. CTimer match rate shown through external pin

In the image below, an example is shown of the ADC result when measuring 3.3 V. We should expect the maximum value printed in our terminal window for the 16-bit resolution, in this case 65535. To change the converted value, change the voltage on pin PIO1\_9, on header J7 pin 1 on LPC55S36-EVK.



Figure 9. Printed results shown from measuring 3.3 V source

## 5 ADC calculation tool

The objective of the tool attached to this application note is to define max sampling rates that can be achieved depending on the input signal impedance characteristics. In order to sample the input voltage accurately, the source resistance, and ADC sample time must be chosen appropriately. For a fixed source resistance ( $R_{AS}$ ), the required sample time is given by:

$$\min t_{SMP} = B \times [R_{AS} \times (C_{AS} + C_P + C_{ia}) + C_{ia} \times (R_{AS} + R_I)]$$

$$B = -\ln \left( \frac{LSB_{ERR}}{2^N} \right)$$

N – ADC resolution, that is, 12 for 13-bit and 12-bit mode, 16 for 16-bit mode.

LSB<sub>ERR</sub> -- value of acceptable sampling error in LSBs, that is, sampling within ¼ LSB accuracy.

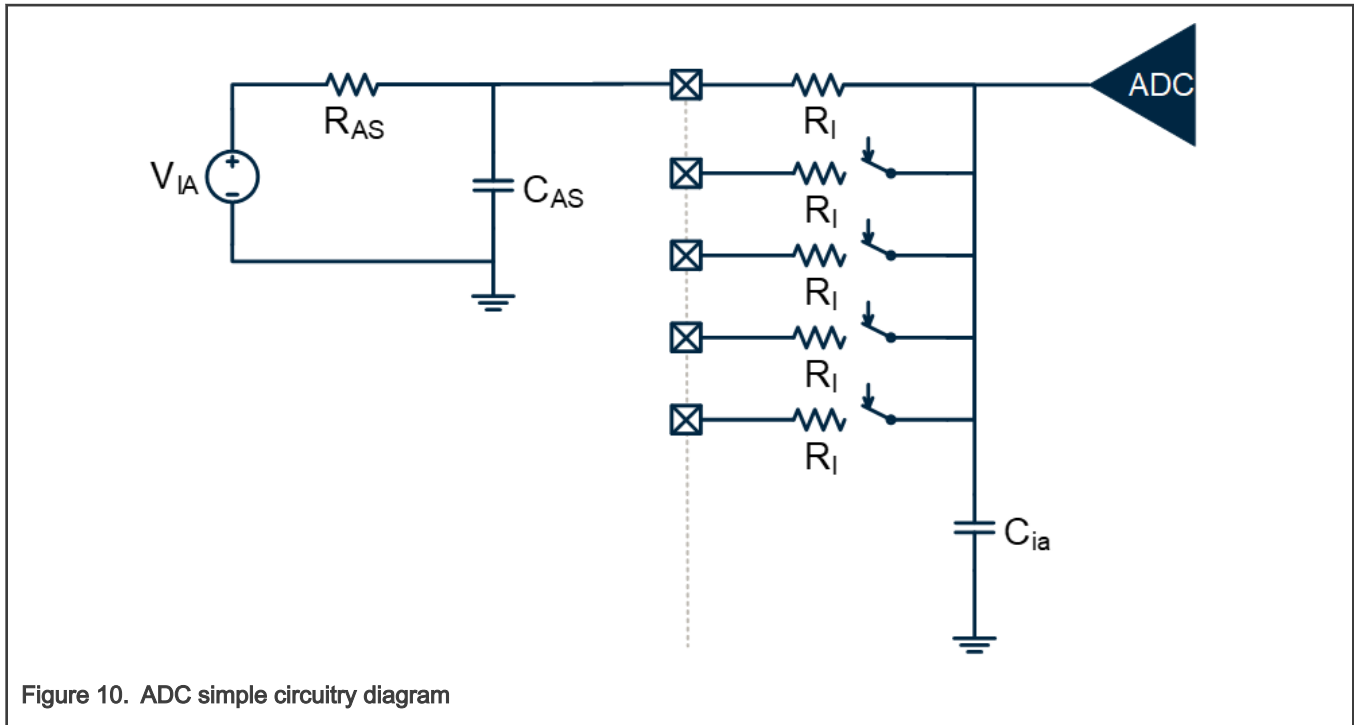


Figure 10. ADC simple circuitry diagram

Where B is the adjusted resolution based on the chosen sampling error. The user configured sample time is determined by the ADC input clock frequency ( $f_{ADCK}$ ) and the Sample Time Select (STS) bits in the ADC command register which choose the number of the sample cycles. When STS is programmed to a non-zero value, the sample time is  $(3 + 2^{STS})$  ADCK cycles. The shortest sample time maximizes conversion speed for lower impedance inputs. Extending sample time allows higher impedance inputs to be accurately sampled:

$$user\ t_{SMP} = \frac{user\ STS}{f_{ADCK}}$$

User<sub>STS</sub> is the number of ADC clock cycles during the sample time, and is programmable 3, 5, 7, 11, 19, 35, 67 or 131 ADCK cycles ( $user\ STS \geq min\ STS$ ), it depends on the value chosen at register CMDHn[STS]. User<sub>t<sub>SMP</sub></sub> must be configured to be greater than or equal to min<sub>t<sub>SMP</sub></sub>. If we set  $user\ t_{SMP} > min\ t_{SMP}$  and solve for  $R_{AS}$ , we can find the maximum source resistance that would allow us to sample at the desired accuracy:

$$R_{AS} < \frac{\frac{user\ STS}{f_{ADCK} \times B} - (R_I \times C_{ia})}{C_{AS} + C_P + 2C_{ia}}$$

Table 2. ADC sample time calculator

ADC min Sample Time $t_{SMP}$ min sample time based on a fixed $R_{AS}$		
Input... enter yellow highlighted cells		
Resolution	16 bits	
$C_{AS}$	100E-12 F	
$R_{AS}$	5.0E+3 $\Omega$	
LSB <sub>ERR</sub>	1/8 LSB	
$C_P$	3E-12 F	
$C_{ia}$	4E-12 F	
B	13.17	
<hr/>		
	$R_i(\Omega)$	min $t_{SMP}$
<b>High Speed</b>		
$V_{REFP} = 1.8V$	1.6E+3	7.39E-6
$V_{REFP} = 3.0V$	1.1E+3	7.37E-6
<b>Standard Muxed</b>		
$V_{REFP} = 1.8V$	3.2E+3	7.48E-6
$V_{REFP} = 3.0V$	1.8E+3	7.40E-6
<b>Standard Dedicated</b>		
$V_{REFP} = 1.8V$	300	7.33E-6
$V_{REFP} = 3.0V$	300	7.33E-6
<b>Internal</b>		
$V_{REFP} = 1.8V$	1.9E+3	7.41E-6
$V_{REFP} = 3.0V$	1.1E+3	7.37E-6

The first section of this tool, is as shown on the left. This table specifies the required sample time for a fixed  $R_{AS}$ .

The user can input the source resistance, source capacitance (both external components), the resolution, and the value of the acceptable sampling error in LSB (LSB<sub>ERR</sub>) of the ADC.

The following values provided in the LPC553x/LPC55S3x Data Sheet.

$C_P$  – Parasitic Cap of pad/package

$C_{ia}$  – Input Capacitance

$R_i$  – Input Resistance

Table 3. ADC sampling frequency and  $R_{AS}$  calculator

ADC Conversion Time $CT$ and $R_{AS}$ Calculator							
To calculate maximum $R_{AS}$ with given sample time and ADC input clock frequency							
Input... enter yellow highlighted cells							
Resolution	12 bits	Sample Time Select	131	ADCK			
$C_{AS}$	1E-9 F	Hardware Average	1				
ADC Source CLK	100E+6 Hz	Power Select	high power				
ADCnCLKDIV[DIV]	3						
LSB <sub>ERR</sub>	1/2 LSB						
$C_P$	3E-12 F						
$C_{ia}$	4E-12 F						
B	9.01						
$f_{ADCK}$	33E+6 MHz	$\max f_{ADCK}$	60.0E+6 MHz				
<hr/>							
	$R_i(\Omega)$	min STS	user STS	user $t_{SMP}$	max $R_{AS}$	CT	MspS
<b>High Speed</b>							
$V_{REFP} = 1.8V$	1.6E+3	5	131	3.9E-6	426.7E+0	4.4E-6	0.23
$V_{REFP} = 3.0V$	1.1E+3	5	131	3.9E-6	428.7E+0	4.4E-6	0.23
<b>Standard Muxed</b>							
$V_{REFP} = 1.8V$	3.2E+3	5	131	3.9E-6	420.4E+0	4.4E-6	0.23
$V_{REFP} = 3.0V$	1.8E+3	5	131	3.9E-6	425.9E+0	4.4E-6	0.23
<b>Standard</b>							
$V_{REFP} = 1.8V$	300	5	131	3.9E-6	431.9E+0	4.4E-6	0.23
$V_{REFP} = 3.0V$	300	5	131	3.9E-6	431.9E+0	4.4E-6	0.23
<b>Internal</b>							
$V_{REFP} = 1.8V$	1.9E+3	5	131	3.9E-6	425.6E+0	4.4E-6	0.23
$V_{REFP} = 3.0V$	1.1E+3	5	131	3.9E-6	428.7E+0	4.4E-6	0.23

The next section of the tool, can provide the maximum source resistance based on the sample time and ADC frequency that is used.

As in the previous section, the user can change the yellow cells according to the parameters that they are working with.

The following are some other parameters that are given in the calculator tool.

$f_{ADCK}$  - Input clock frequency

$CYC_{SMP\_MIN}$  - Min sample cycles required for  $T_{SMP} > T_{SMP\_REQ}$

$CYC_{SMP\_USER}$  – Sample cycles set the user using CMDHn[STS]

$T_{SMP}$  – Sample time set the user.

## 6 ADC basic concepts

**Resolution:** The number of bits in the ADC digital output representing an analog input signal. For LPC553x/LPC55S3x, the resolution can be configured to 12, 13 and 16-bit resolution.

**Reference Voltage:** The ADC requires a reference voltage used to create a successive approximation comparison with the analog input to produce a digital output. The digital output is the ratio of the analog input with respect to this reference voltage.

$$V_{REF} = V_{REFH} - V_{REFL}$$

Where:  $V_{REFH}$  = High reference voltage  $V_{REFL}$  = Low reference voltage

**ADC output formula:** The conversion equation of ADC is used to calculate the digital output corresponding to a particular analog input voltage. This equation assumes an ideal A/D conversion with no introduced errors.

$$ADC \text{ Digital Output} = \frac{2^N * \text{Analog Input Voltage}}{\text{Reference Voltage}}$$

$N$  = ADC Resolution. For the LPC553x this can be 12/13/16

**Least Significant Bits (LSB):** A least significant bit (LSB) is a unit of voltage equal to the smallest resolution of the ADC, that is, the smallest incremental voltage that causes a change in the digital output. The LSB is equal to the reference voltage divided by the maximum count of the ADC:

$$LSB = V_{REF} / 2^N$$

$N$  = ADC resolution

$V_{REF}$  = Analog reference voltage

**ADC Actual Transfer Function:** The ADC converts an input voltage to a corresponding digital code. The curve describing this behavior is the actual transfer function and includes all the errors inherent to the ADC module itself.

**ADC Ideal Transfer Function:** The ideal transfer function represents the behavior of the ADC assuming it is perfectly linear, or that a given change in input voltage creates the same change in conversion code regardless of the input's initial level.

## 7 Sources of error in ADC measurements

This section presents some typical factors that prevent the ADC from performing accurate A/D measurements.

**Reference voltage noise:** The ADC output is directly proportional to the analog input voltage and the reference voltage. An unstable reference voltage (for example, caused by noise in the supply rail) causes the changes in the converted digital outputs. For example, a reference voltage of 5 V and an input voltage of 1 V gives 819 for a 12-bit resolution using the ADC output formula. With a 50 mV increase in the absolute reference voltage (that is,  $V_{REF} = 5.05$  V), the new converted value for the same 1 V input voltage is now 811. The resulting reference voltage noise error is  $811 - 819 = -8$  LSB.

**Analog input signal noise:** Small but high-frequency variations in the analog input signal can potentially cause big conversion errors during ADC sampling time. Noise can be induced by electromagnetic emissions from surrounding electrical devices (EMI noise). Therefore, the conversion accuracy is negatively impacted. If the noise present in the input signal is higher than 1LSB, this effectively reduces the number of reliable bits in the conversion result, since the least significant bits are constantly changing due to the signal variations.

**Analog-signal source resistance:** The impedance of the analog signal source or series resistance ( $R_{IN}$ ) between the source and the input pin causes a voltage drop across it because of the current flowing into the pin.

**Temperature influence:** The temperature of the system can have a major influence on ADC accuracy, mainly causing offset error drift and gain error drift. The ADC reference voltage also changes with temperature change. These errors can be compensated with adjustments to the microcontroller firmware, such as monitoring the internal bandgap voltage to verify that the reference voltage has not changed or characterizing the system over the application's temperature range to account for the errors.

## 8 References

- LPC553x/LPC55S3x Reference Manual



- [LPC553x/LPC55S3x Data Sheet](#)
- [LPC553x/LPC55S3x Errata](#)
- [Hardware Design Guidelines for LPC55\(S\)xx Microcontrollers \(document \[AN13033\]\(#\)\)](#)

## 9 Revision history

[Table 4](#) is the revision history table.

Table 4. Revision history

Revision number	Date	Substantive changes
1	20 April 2022	Updated <a href="#">ADC calculation tool</a>
0	2 February 2022	Initial release

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